

# Product Change Notification - JAON-17ZYGR178

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**Date:** 23 Jan 2015

**Product Category:** Supertex

**Notification subject:** CCB 1409.09 Final Notice - Additional Fabrication Site: Qualification of an additional fabrication site for HT0440, HT0740, HV9110, HV9112, HV9113, HV9120, HV9123, LR645, LR745 and LR8 Supertex device

**Notification text:** **PCN Status:**

Final notification

**Microchip Parts Affected:**

See attachments of affected catalog part numbers (CPN) labeled as...

PCN\_JAON-17ZYGR178\_Affected\_CPN.xls

PCN\_JAON-17ZYGR178\_Affected\_CPN.pdf

**Description of Change:**

Qualification of an additional fabrication site for HT0440, HT0740, HV9110, HV9112, HV9113, HV9120, HV9123, LR645, LR745 and LR8 Supertex device families.

**Pre Change:**

Fabricated at SPTX fab site.

**Post Change:**

Fabricated at Microchip FAB2 fab site.

**Impacts to Data Sheet:**

No

**Reason for Change:**

To improve productivity as part of the integration of Supertex and Microchip.

NOTE: SPTX will no longer have the ability to start additional wafers as of Q4 of CY14.

**Change Implementation Status:**

Complete

**Estimated First Ship Date:**

February 23, 2015 (date code: 1509)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

**Markings to Distinguish Revised from Unrevised Devices:**

Traceability code

**Revision History:**

**July 15, 2014:** Issued initial notification as PCN number JAON-15TRYZ317.

**August 14, 2014:** Revised the initial notification by revising the CPN list to include all parts that are moving to FAB2, adding the note after the reason for change, and revising the customer letter to show that Supertex customers may register for Microchip's PCN email service.

**January 23, 2015:** Issued final notification. Attached the Qualification Report. Updated Impacts to Data Sheet from TBD to No. Revised the estimated first ship date from September 12, 2014 to February 23, 2015.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

**Attachment(s):** [PCN\\_JAON-17ZYGR178\\_Qual\\_Report.pdf](#) [PCN\\_JAON-17ZYGR178\\_Affected\\_CPN.pdf](#) [PCN\\_JAON-17ZYGR178\\_Affected\\_CPN.xls](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

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PCN_JAON-17ZYGR178
CATALOG PART_NBR
HT0440K6-G
HT0440LG-G
HT0740LG-G
HV9110NG-G
HV9110NG-G-SM267
HV9110NW
HV9110X
HV9112NG-G
HV9113NG-G
HV9113X
HV9120NG-G
HV9120NG-G-M901
HV9120P-G
HV9123NG-G
HV9123NG-G-M901
HV9123NG-G-M934
HV9123P-G
HV9123X
LR645LG-G
LR645N3-G
LR645N3-G-P003
LR645N3-G-P013
LR645N5-G
LR645N8-G
LR745N3-G
LR745N3-G-P003
LR745N3-G-P013
LR745N8-G
LR8K4-G
LR8N3-G
LR8N3-G-P003
LR8N8-G



**PCN #: JAON-17ZYGR178**

**Date:  
January 16, 2015**

**Qualification of an additional fabrication site for HT0440,  
HT0740, HV9110, HV9112, HV9113, HV9120, HV9123, LR645,  
LR745 and LR8 Supertex device families**

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## QUALIFICATION DATA

### Infant Mortality Life / Early Life Failure Rate

Test Method	JESD22-A 108
Test Condition	125°C / 96 hours
Sample Size (250 ea)	(Fail/Pass)
Lot 1	0/250

### High Temperature Operating Life

Test Method	JESD22-A 108
Test Condition	125°C / 1000 hours
Sample Size (45 ea. min)	(Fail/Pass)
Lot 1	0/45

### ESD

Test	Reference Method	Sample Size	Result
ESD – HBM	JESD22-A114	Lot 1 = 3ea	±1000V @ 25°C
Latch-up	JESD78	Lot 1 = 6ea	Pass @ 25°C